

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/802,628	SATOH, TOMIO	
Examiner	Art Unit	
Joseph Chang	2817	

	SEARCHED		
Class	Subclass	Date	Examiner
331	116R, 117R	6/17/2005	1C
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
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